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X8	Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 14544-002001	Application No. 09/787,358	
(O) DUT	nformation Disclosure Statement by Applicant		Applicant Philip Marriott		
		neets if necessary)	Filing Date May 15, 2001	Group Art Unit 2881	

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Information Disclosure Statement

Applicant
Philip Marriott

by Applicant (Use several sheets if necessary)

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